

SI2334DS-T1-E3-VB Datasheet

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
30	0.030 at V _{GS} = 10 V	6.5	4.5 nC			
30	0.033 at V _{GS} = 4.5 V	6.0	4.5 110			

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET

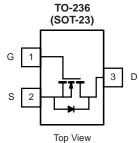
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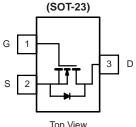
- 100 % R_g Tested ٠
- Compliant to RoHS Directive 2002/95/EC ٠

APPLICATIONS

DC/DC Converter







S N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	30	V		
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		6.5 ^a		
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	T _C = 70 °C		6.0		
	T _A = 25 °C	טי ד	5.3		
	T _A = 70 °C	1 [5.0	A	
Pulsed Drain Current		I _{DM}	25		
	T _C = 25 °C		1.4		
Continuous Source-Drain Diode Current	T _A = 25 °C	Is	0.9 ^{b, c}		
	T _C = 25 °C		1.7		
Maximum Power Dissipation	T _C = 70 °C	P _D	1.1	w	
Maximum Fower Dissipation	T _A = 25 °C		1.1 ^{b, c}	VV	
	T _A = 70 °C	1 [0.7 ^{b, c}		
Operating Junction and Storage Temperatur	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temperations)		260			

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	90	115	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	60	75	0/11		

Notes:

a. Package limited

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 130 °C/W.

SPECIFICATIONS $T_J = 25 \text{ °C}$, Parameter	Symbol	Test Conditions	Min.	Tun	Max.	Unit	
	Symbol	Test Conditions	win.	Тур.	wax.	Unit	
Static	V)/0)/_L250.uA	20				
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		31		mV/°(
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	0.7	1.1	2.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 V, V_{GS} = 0 V$			1	μA	
	-033	V_{DS} = 30 V, V_{GS} = 0 V, T_{J} = 55 °C			10	μ.,	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, V_{GS} = 10 V	10			Α	
	D	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3.2 \text{ A}$		0.030		0	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_{D} = 2.8 \text{ A}$		0.033		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 4.8 A		11		S	
Dynamic ^b	<u> </u>						
Input Capacitance	C _{iss}			335		pF	
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		45			
Reverse Transfer Capacitance	C _{rss}	20 00		17			
·		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 3.4 A		4.5	6.7	<u> </u>	
Total Gate Charge	Charge Q_g		2.1	3.2			
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 3.4 \text{ A}$		0.85		nC	
Gate-Drain Charge	Q _{gd}			0.65			
Gate Resistance	R _q	f = 1 MHz	0.8	4.4	8.8	Ω	
Turn-On Delay Time	t _{d(on)}			12	20		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_1 = 5.6 \Omega$		50	75	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 2.7 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		12	20		
Fall Time	t _f			22	35		
Turn-On Delay Time	t _{d(on)}			5	10	ns	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_{1} = 5.6 \Omega$		12	20	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 2.7 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_a = 1 \Omega$		10	15		
Fall Time	t _f			5	10		
Drain-Source Body Diode Characteristic							
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			1.4		
Pulse Diode Forward Current	I _{SM}	-			15	A	
Body Diode Voltage	V _{SD}	I _S = 2.7 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			10	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			5	10	nC	
Reverse Recovery Fall Time	t _a	$I_F = 2.7 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 \text{ °C}$		6			
Reverse Recovery Rise Time	t _a			4		ns	

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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- 55 $T_C =$

T_C = 25

2.0

T_C = 125 °C

V_{GS} - Gate-to-Source Voltage (V)

Transfer Characteristics

1.5

Ciss

1.0

Coss

0

25

50

T_J - Junction Temperature (°C)

75

100

125 150

10

15

V_{DS} - Drain-to-Source Voltage (V)

Capacitance

20

 $V_{GS} = 10$ V

25

30

5

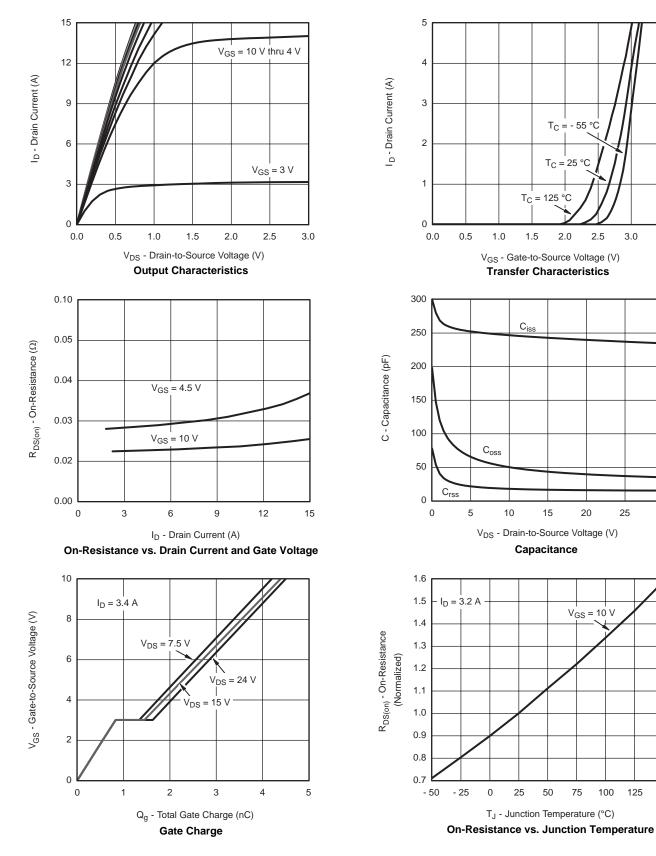
°C

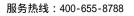
2.5

3.0

3.5

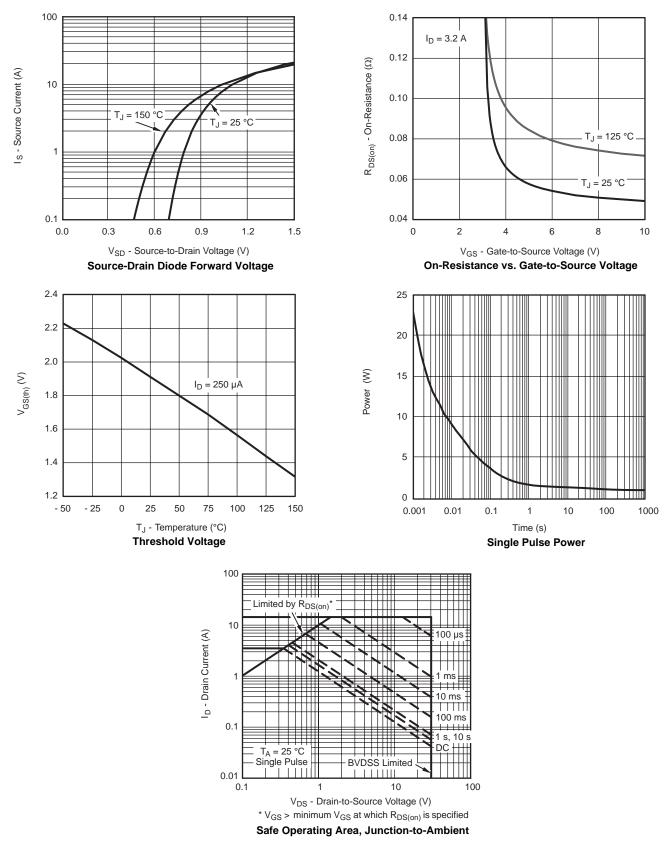
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





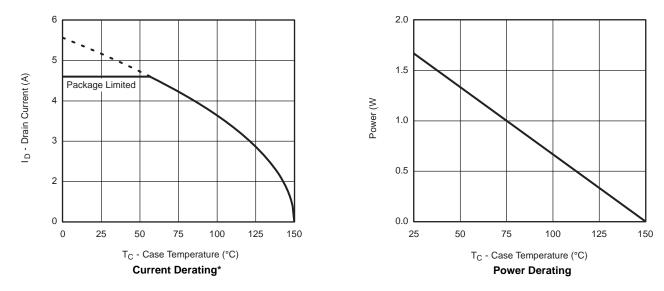


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





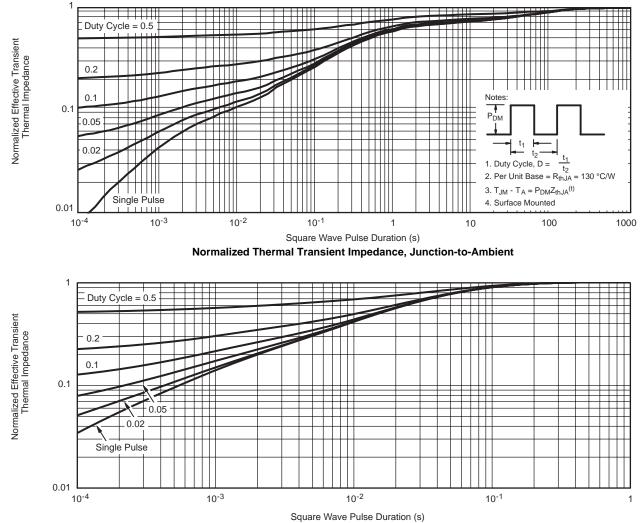
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-23 (TO-236): 3-LEAD







Dim	MILLIN	METERS	INCHES		
	Min	Max	Min	Мах	
Α	0.89	1.12	0.035	0.044	
A ₁	0.01	0.10	0.0004	0.004	
A ₂	0.88	1.02	0.0346	0.040	
b	0.35	0.50	0.014	0.020	
C	0.085	0.18	0.003	0.007	
D	2.80	3.04	0.110	0.120	
E	2.10	2.64	0.083	0.104	
E ₁	1.20	1.40	0.047	0.055	
е	0.95 BSC		0.0374 Ref		
e ₁	1.90 BSC		0.0748 Ref		
L	0.40	0.60	0.016	0.024	
L ₁	0.64 Ref		0.025 Ref		
S	0.50 Ref		0.020 Ref		
q	3°	8°	3°	8°	
ECN: S-03946-Rev. K, 09- DWG: 5479	Jul-01				

SI2334DS-T1-E3-VB



RECOMMENDED MINIMUM PADS FOR SOT-23



Recommended Minimum Pads Dimensions in Inches/(mm)

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